Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/633,620	KATO ET AL.
Examiner	Art Unit
Quynh H. Nguyen	2614

SEARCHED			
Class	Subclass	Date	Examiner
379	90.01 93.01 93.09 210.01 230	4/27/07	QN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			,

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Searched: East, USPGPub, USPAT, EPO, JPO	4/27/07	QN
Inventor search in PALM database	4/27/07	QN
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